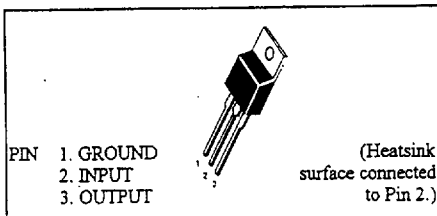


FEATURES

- No External Components Required
- Internal Thermal Overload Protection
- Internal Short-Circuit Current Limiting
- Output Transistor Safe-Area Compensation
- Available in 2% Voltage Tolerance (See Ordering Information)

PIN ARRANGEMENT

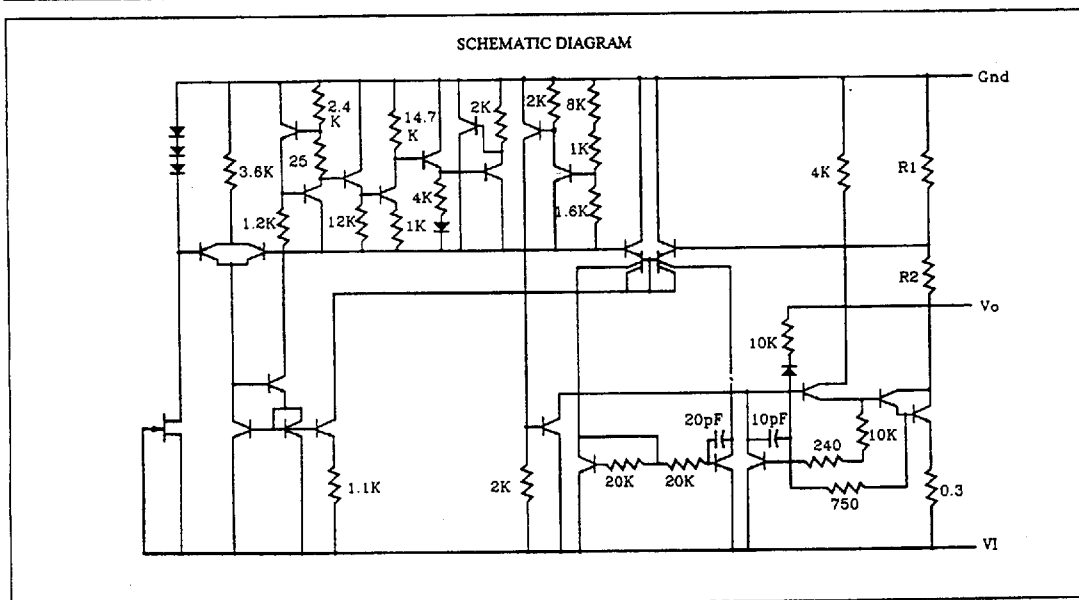


THREE-TERMINAL NEGATIVE VOLTAGE REGULATORS

The LM7900 Series of fixed output negative voltage regulators are intended as complements to the popular LM7800 Series devices. These negative regulators are available in the same seven-voltage options as the LM7800 devices. In addition, one extra voltage option commonly employed in MECL systems is also available in the negative LM7900 Series.

Available in fixed output voltage options from -5.0 to -24 volts, these regulators employ current limiting, thermal shutdown, and safe-area compensation—making them remarkably rugged under most operating conditions. With adequate heatsinking they can deliver output currents in excess of 1.5 ampere.

CIRCUIT SCHEMATIC



ABSOLUTE MAXIMUM RATINGS (Ta=25°C)

Item	Symbol	LM7900 Series	Unit
Input Voltage	Vin *1	-30	V
Input Voltage	Vin *2	-40	V
Power Dissipation	P _D *3	15	W
Operating Ambient Temperature	T _{opr}	-20 to +75	°C
Operating Junction Temperature	T _j	-20 to +125	°C
Storage Temperature	T _{stg}	-55 to +125	°C

Note: *1: LM7905, LM7906, LM7908, LM7909, LM7912, LM7915, LM7918

*2: LM7924

*3: Follow the derating curve. When T_j exceeds 150°C, the internal circuit cuts off the output.

LM7905 ELECTRICAL CHARACTERISTICS

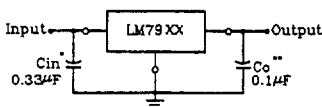
(V_{in}=-10V, I_{out}=500mA, C_{in}=2μF, C_{out}=1μF; T_j=0°C to 125°C, unless otherwise specified.)

Item	Symbol	Test Circuit	Condition	Min.	Typ.	Max.	Unit
Output Voltage	V _o	1	T _j =25°C	-4.9	-5.0	-5.1	V
Output Voltage Tolerance	V _o	1	V _i =-7 to -20V, I _o =5mA to 1A, P _D <15W	-4.85	—	-5.15	V
Line Regulation	REG _{line}	1	T _j =25°C	—	3	100	mV
					1	50	mV
Load Regulation	REG _{load}	1	T _j =25°C	—	10	100	mV
					3	50	mV
Bias Current	I _{IB}	2	T _j =25°C	—	2	4	mA
Input Bias Current Fluctuation	ΔI _{IB} Input	2	V _i =-7 to -25V, T _j =25°C	—	—	1.3	mA
Load Bias Current Fluctuation	ΔI _{IB} Load	2	I _o =5mA to 1A, T _j =25°C	—	—	0.5	mA
Output Noise Voltage	V _n	1	f=10Hz to 100KHz, T _a =25°C	—	40	—	μV
Ripple Rejection Ratio	RR	3	V _i =-8 to -18V, I _o =100mA, f=120Hz	62	74	—	dB
Min. I/O Voltage Difference	V _{dif}		I _o =1A, T _j =25°C	—	1.1	—	V
Peak Output Current	I _o -peak	1	T _j =25°C	—	2.1	—	A
Output Voltage Temperature Coefficient	ΔV _o /Ta	1	I _o =5mA, T _j =0 to 125°C	—	-0.4	—	mV/°C

Note: The specified condition T_j=25°C means that the test should be carried out with the test time so short (within 10mS), that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

TYPICAL CONNECTING CIRCUIT

STANDARD APPLICATION



A common ground is required between the input and the output voltages. The input voltage must remain typically 2.0 V more negative even during the high point on the input ripple voltage.

XX = these two digits of the type number indicate voltage.

* C_{in} is required if regulator is located an appreciable distance from power supply filter.

** C_o improves stability and transient response.

LM7906 ELECTRICAL CHARACTERISTICS

($V_{in} = -11V$, $I_{out} = 500mA$, $C_{in} = 2\mu F$, $C_{out} = 1\mu F$; $T_j = 0^\circ C$ to $125^\circ C$, unless otherwise specified.)

Item	Symbol	Test Circuit	Condition	Min.	Typ.	Max.	Unit
Output Voltage	V_o	1	$T_j = 25^\circ C$	-5.88	-6	-6.12	V
Output Voltage Tolerance	V_o	1	$V_i = -8$ to $-21V$, $I_o = 5mA$ to $1A$, $P_D < 15W$	-5.83	—	-6.17	V
Line Regulation	REGline	1	$T_j = 25^\circ C$	$V_i = -8$ to $-25V$	—	4	120 mV
				$V_i = -9$ to $-13V$	—	1.5	60 mV
Load Regulation	REGload	1	$T_j = 25^\circ C$	$I_o = 5mA$ to $1.5A$	—	10	120 mV
				$I_o = 250mA$ to $750mA$	—	3	60 mV
Bias Current	I_{IB}	2	$T_j = 25^\circ C$	—	2	4	mA
Input Bias Current Fluctuation	ΔI_{IB} Input	2	$V_i = -8$ to $-25V$, $T_j = 25^\circ C$	—	—	1.3	mA
Load Bias Current Fluctuation	ΔI_{IB} Load	2	$I_o = 5mA$ to $1A$, $T_j = 25^\circ C$	—	—	0.5	mA
Output Noise Voltage	V_n	1	$f = 10Hz$ to $100KHz$, $T_a = 25^\circ C$	—	44	—	μV
Ripple Rejection Ratio	RR	3	$V_i = -9$ to $-19V$, $I_o = 100mA$, $f = 120Hz$	60	73	—	dB
Min. I/O Voltage Difference	V_{dif}		$I_o = 1A$, $T_j = 25^\circ C$	—	1.1	—	V
Peak Output Current	I_o -peak	1	$T_j = 25^\circ C$	—	2.1	—	A
Output Voltage Temperature Coefficient	$\Delta V_o/T_a$	1	$I_o = 5mA$, $T_j = 0$ to $125^\circ C$	—	-0.5	—	mV/ $^\circ C$

Note: The specified condition $T_j = 25^\circ C$ means that the test should be carried out with the test time so short (within 10mS), that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

LM7908 ELECTRICAL CHARACTERISTICS

($V_{in} = -14V$, $I_{out} = 500mA$, $C_{in} = 2\mu F$, $C_{out} = 1\mu F$; $T_j = 0^\circ C$ to $125^\circ C$, unless otherwise specified.)

Item	Symbol	Test Circuit	Condition	Min.	Typ.	Max.	Unit
Output Voltage	V_o	1	$T_j = 25^\circ C$	-7.84	-8	-8.16	V
Output Voltage Tolerance	V_o	1	$V_i = -10.5$ to $-23V$, $I_o = 5mA$ to $1A$, $P_D < 15W$	-7.74	—	-8.26	V
Line Regulation	REGline	1	$T_j = 25^\circ C$	$V_i = -10.5$ to $-25V$	—	6	160 mV
				$V_i = -11$ to $-17V$	—	2	80 mV
Load Regulation	REGload	1	$T_j = 25^\circ C$	$I_o = 5mA$ to $1.5A$	—	12	160 mV
				$I_o = 250mA$ to $750mA$	—	4	80 mV
Bias Current	I_{IB}	2	$T_j = 25^\circ C$	—	2.2	4.5	mA
Input Bias Current Fluctuation	ΔI_{IB} Input	2	$V_i = -10.5$ to $-25V$, $T_j = 25^\circ C$	—	—	1	mA
Load Bias Current Fluctuation	ΔI_{IB} Load	2	$I_o = 5mA$ to $1A$, $T_j = 25^\circ C$	—	—	0.5	mA
Output Noise Voltage	V_n	1	$f = 10Hz$ to $100KHz$, $T_a = 25^\circ C$	—	52	—	μV
Ripple Rejection Ratio	RR	3	$V_i = -11$ to $-21V$, $I_o = 100mA$, $f = 120Hz$	56	71	—	dB
Min. I/O Voltage Difference	V_{dif}		$I_o = 1A$, $T_j = 25^\circ C$	—	2	—	V
Peak Output Current	I_o -peak	1	$T_j = 25^\circ C$	—	2.1	—	A
Output Voltage Temperature Coefficient	$\Delta V_o/T_a$	1	$I_o = 5mA$, $T_j = 0$ to $125^\circ C$	—	-0.6	—	mV/ $^\circ C$

Note: The specified condition $T_j = 25^\circ C$ means that the test should be carried out with the test time so short (within 10mS), that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

LM7909 ELECTRICAL CHARACTERISTICS

($V_{in} = -15V$, $I_{out} = 500mA$, $C_{in} = 2\mu F$, $C_{out} = 1\mu F$; $T_j = 0^\circ C$ to $125^\circ C$, unless otherwise specified.)

Item	Symbol	Test Circuit	Condition	Min.	Typ.	Max.	Unit
Output Voltage	V_o	1	$T_j = 25^\circ C$	-8.82	-9	-9.18	V
Output Voltage Tolerance	V_o	1	$V_i = 11.5$ to $-24V$, $I_o = 5mA$ to $1A$, $P_D < 15W$	-8.72	—	-9.28	V
Line Regulation	REG _{line}	1	$T_j = 25^\circ C$ $V_i = 11.5$ to $-26V$	—	7	180	mV
			$V_i = 12$ to $-18V$	—	2	90	mV
Load Regulation	REG _{load}	1	$T_j = 25^\circ C$ $I_o = 5mA$ to $1.5A$	—	12	180	mV
			$I_o = 250mA$ to $750mA$	—	4	90	mV
Bias Current	I_{IB}	2	$T_j = 25^\circ C$	—	2.2	4.5	mA
Input Bias Current Fluctuation	ΔI_{IB} Input	2	$V_i = 11.5$ to $-26V$, $T_j = 25^\circ C$	—	—	1	mA
Load Bias Current Fluctuation	ΔI_{IB} Load	2	$I_o = 5mA$ to $1A$, $T_j = 25^\circ C$	—	—	0.5	mA
Output Noise Voltage	V_n	1	$f = 10Hz$ to $100KHz$, $T_a = 25^\circ C$	—	58	—	μV
Ripple Rejection Ratio	RR	3	$V_i = 12$ to $-22V$, $I_o = 100mA$, $f = 120Hz$	56	71	—	dB
Min. I/O Voltage Difference	V_{dif}		$I_o = 1A$, $T_j = 25^\circ C$	—	1.1	—	V
Peak Output Current	I_o -peak	1	$T_j = 25^\circ C$	—	2.1	—	A
Output Voltage Temperature Coefficient	$\Delta V_o/T_a$	1	$I_o = 5mA$, $T_j = 0$ to $125^\circ C$	—	-0.6	—	mV/ $^\circ C$

Note: The specified condition $T_j = 25^\circ C$ means that the test should be carried out with the test time so short (within 10mS), that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

LM7912 ELECTRICAL CHARACTERISTICS

($V_{in} = -19V$, $I_{out} = 500mA$, $C_{in} = 2\mu F$, $C_{out} = 1\mu F$; $T_j = 0^\circ C$ to $125^\circ C$, unless otherwise specified.)

Item	Symbol	Test Circuit	Condition	Min.	Typ.	Max.	Unit
Output Voltage	V_o	1	$T_j = 25^\circ C$	-11.76	-12	-12.24	V
Output Voltage Tolerance	V_o	1	$V_i = 14.5$ to $-27V$, $I_o = 5mA$ to $1A$, $P_D < 15W$	-11.66	—	-12.34	V
Line Regulation	REG _{line}	1	$T_j = 25^\circ C$ $V_i = 14.5$ to $-30V$	—	10	240	mV
			$V_i = 16$ to $-22V$	—	3	120	mV
Load Regulation	REG _{load}	1	$T_j = 25^\circ C$ $I_o = 5mA$ to $1.5A$	—	12	240	mV
			$I_o = 250mA$ to $750mA$	—	4	120	mV
Bias Current	I_{IB}	2	$T_j = 25^\circ C$	—	2.5	5	mA
Input Bias Current Fluctuation	ΔI_{IB} Input	2	$V_i = 14.5$ to $-30V$, $T_j = 25^\circ C$	—	—	1	mA
Load Bias Current Fluctuation	ΔI_{IB} Load	2	$I_o = 5mA$ to $1A$, $T_j = 25^\circ C$	—	—	0.5	mA
Output Noise Voltage	V_n	1	$f = 10Hz$ to $100KHz$, $T_a = 25^\circ C$	—	75	—	μV
Ripple Rejection Ratio	RR	3	$V_i = 15$ to $-25V$, $I_o = 100mA$, $f = 120Hz$	55	70	—	dB
Min. I/O Voltage Difference	V_{dif}		$I_o = 1A$, $T_j = 25^\circ C$	—	1.1	—	V
Peak Output Current	I_o -peak	1	$T_j = 25^\circ C$	—	2.1	—	A
Output Voltage Temperature Coefficient	$\Delta V_o/T_a$	1	$I_o = 5mA$, $T_j = 0$ to $125^\circ C$	—	-0.8	—	mV/ $^\circ C$

Note: The specified condition $T_j = 25^\circ C$ means that the test should be carried out with the test time so short (within 10mS), that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

LM7915 ELECTRICAL CHARACTERISTICS

($V_{in} = -23V$, $I_{out} = 500mA$, $C_{in} = 2\mu F$, $C_{out} = 1\mu F$; $T_j = 0^\circ C$ to $125^\circ C$, unless otherwise specified.)

Item	Symbol	Test Circuit	Condition	Min.	Typ.	Max.	Unit
Output Voltage	V_o	1	$T_j = 25^\circ C$	-14.7	-15	-15.3	V
Output Voltage Tolerance	V_o	1	$V_i = -17.5$ to $-30V$, $I_o = 5mA$ to $1A$, $P_D < 15W$	-14.55	—	-15.45	V
Line Regulation	REG _{line}	1	$T_j = 25^\circ C$	—	11	300	mV
			$V_i = -17.5$ to $-30V$	—	3	150	mV
Load Regulation	REG _{load}	1	$T_j = 25^\circ C$	—	12	300	mV
			$I_o = 5mA$ to $1.5A$	—	4	150	mV
			$I_o = 250mA$ to $750mA$	—	—	—	mV
Bias Current	I_{IB}	2	$T_j = 25^\circ C$	—	2.5	5	mA
Input Bias Current Fluctuation	ΔI_{IB} Input	2	$V_i = -17.5$ to $-30V$, $T_j = 25^\circ C$	—	—	1	mA
Load Bias Current Fluctuation	ΔI_{IB} Load	2	$I_o = 5mA$ to $1A$, $T_j = 25^\circ C$	—	—	0.5	mA
Output Noise Voltage	V_n	1	$f = 10Hz$ to $100KHz$, $T_a = 25^\circ C$	—	90	—	μV
Ripple Rejection Ratio	RR	3	$V_i = -18.5$ to $-28.5V$, $I_o = 100mA$, $f = 120Hz$	54	69	—	dB
Min. I/O Voltage Difference	V_{dif}		$I_o = 1A$, $T_j = 25^\circ C$	—	1.1	—	V
Peak Output Current	I_o -peak	1	$T_j = 25^\circ C$	—	2.1	—	A
Output Voltage Temperature Coefficient	$\Delta V_o/T_a$	1	$I_o = 5mA$, $T_j = 0$ to $125^\circ C$	—	-0.9	—	mV/ $^\circ C$

Note: The specified condition $T_j = 25^\circ C$ means that the test should be carried out with the test time so short (within 10mS), that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

LM7918 ELECTRICAL CHARACTERISTICS

($V_{in} = -27V$, $I_{out} = 500mA$, $C_{in} = 2\mu F$, $C_{out} = 1\mu F$; $T_j = 0^\circ C$ to $125^\circ C$, unless otherwise specified.)

Item	Symbol	Test Circuit	Condition	Min.	Typ.	Max.	Unit
Output Voltage	V_o	1	$T_j = 25^\circ C$	-17.64	-18	-18.36	V
Output Voltage Tolerance	V_o	1	$V_i = -21$ to $-33V$, $I_o = 5mA$ to $1A$, $P_D < 15W$	-17.54	—	-18.46	V
Line Regulation	REG _{line}	1	$T_j = 25^\circ C$	—	15	360	mV
			$V_i = -21$ to $-33V$	—	5	180	mV
Load Regulation	REG _{load}	1	$T_j = 25^\circ C$	—	12	360	mV
			$I_o = 5mA$ to $1.5A$	—	4	180	mV
			$I_o = 250mA$ to $750mA$	—	—	—	mV
Bias Current	I_{IB}	2	$T_j = 25^\circ C$	—	2.5	5	mA
Input Bias Current Fluctuation	ΔI_{IB} Input	2	$V_i = -21$ to $-33V$, $T_j = 25^\circ C$	—	—	1	mA
Load Bias Current Fluctuation	ΔI_{IB} Load	2	$I_o = 5mA$ to $1A$, $T_j = 25^\circ C$	—	—	0.5	mA
Output Noise Voltage	V_n	1	$f = 10Hz$ to $100KHz$, $T_a = 25^\circ C$	—	110	—	μV
Ripple Rejection Ratio	RR	3	$V_i = -22$ to $-32V$, $I_o = 100mA$, $f = 120Hz$	53	68	—	dB
Min. I/O Voltage Difference	V_{dif}		$I_o = 1A$, $T_j = 25^\circ C$	—	1.1	—	V
Peak Output Current	I_o -peak	1	$T_j = 25^\circ C$	—	2.1	—	A
Output Voltage Temperature Coefficient	$\Delta V_o/T_a$	1	$I_o = 5mA$, $T_j = 0$ to $125^\circ C$	—	-1	—	mV/ $^\circ C$

Note: The specified condition $T_j = 25^\circ C$ means that the test should be carried out with the test time so short (within 10mS), that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

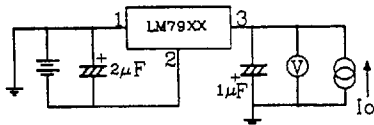
LM7924 ELECTRICAL CHARACTERISTICS

($V_{in} = -33V$, $I_{out} = 500mA$, $C_{in} = 2\mu F$, $C_{out} = 1\mu F$; $T_j = 0^\circ C$ to $125^\circ C$, unless otherwise specified.)

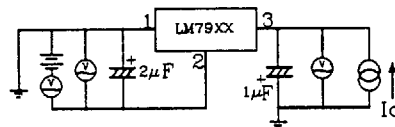
Item	Symbol	Test Circuit	Condition	Min.	Typ.	Max.	Unit
Output Voltage	V_o	1	$T_j = 25^\circ C$	-23.52	-24	-24.48	V
Output Voltage Tolerance	V_o	1	$V_i = -27$ to $-38V$, $I_o = 5mA$ to $1A$, $P_D < 1.5W$	-23.42	—	-24.58	V
Line Regulation	REG _{line}	1	$T_j = 25^\circ C$	—	18	480	mV
			$V_i = -27$ to $-38V$	—	6	240	mV
Load Regulation	REG _{load}	1	$T_j = 25^\circ C$	—	12	480	mV
			$I_o = 5mA$ to $1.5A$	—	4	240	mV
Bias Current	I_{IB}	2	$T_j = 25^\circ C$	—	3	5	mA
Input Bias Current Fluctuation	ΔI_{IB} Input	2	$V_i = -27$ to $-38V$, $T_j = 25^\circ C$	—	—	1	mA
Load Bias Current Fluctuation	ΔI_{IB} Load	2	$I_o = 5mA$ to $1A$, $T_j = 25^\circ C$	—	—	0.5	mA
Output Noise Voltage	V_n	1	$f = 10Hz$ to $100KHz$, $T_a = 25^\circ C$	—	170	—	μV
Ripple Rejection Ratio	RR	3	$V_i = -28$ to $-38V$, $I_o = 100mA$, $f = 120Hz$	50	65	—	dB
Min. I/O Voltage Difference	V_{dif}		$I_o = 1A$, $T_j = 25^\circ C$	—	1.1	—	V
Peak Output Current	I_o -peak	1	$T_j = 25^\circ C$	—	2.1	—	A
Output Voltage Temperature Coefficient	$\Delta V_o / T_a$	1	$I_o = 5mA$, $T_j = 0$ to $125^\circ C$	—	-1	—	mV/ $^\circ C$

Note: The specified condition $T_j = 25^\circ C$ means that the test should be carried out with the test time so short (within 10mS), that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

TEST CIRCUIT 1



TEST CIRCUIT 2



TEST CIRCUIT 3

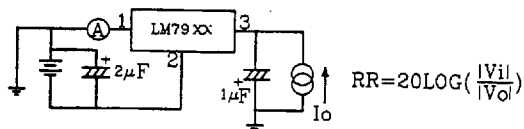


FIGURE 1-WORSE CASE POWER DISSIPATION AS A FUNCTION OF AMBIENT TEMPERATURE

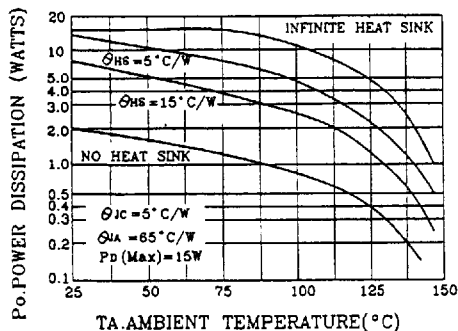


FIGURE 2-WORSE CASE POWER DISSIPATION AS A FUNCTION OF AMBIENT TEMPERATURE

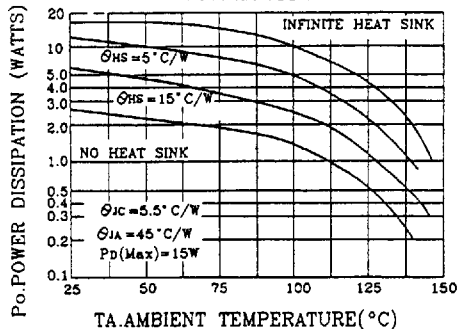


FIGURE 3-PEAK OUTPUT CURRENT AS A FUNCTION OF INPUT-OUTPUT DIFFERENTIAL VOLTAGE

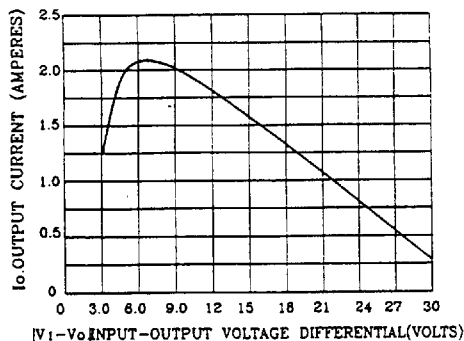


FIGURE 4-RIPPLE REJECTION AS A FUNCTION OF FREQUENCY

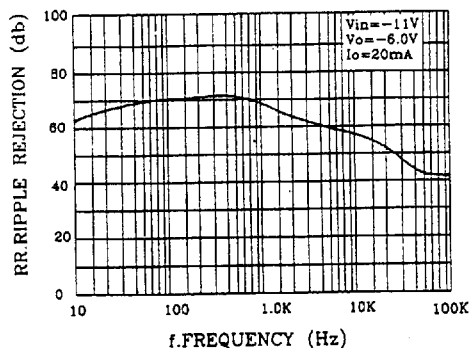


FIGURE 5-RIPPLE REJECTION AS A FUNCTION OF OUTPUT VOLTAGES

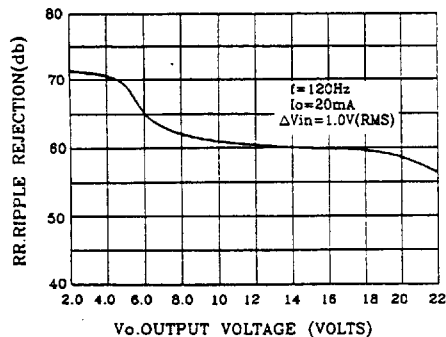


FIGURE 6-OUTPUT VOLTAGE AS A FUNCTION OF JUNCTION TEMPERATURE

